



CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board/AClass
500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

Evans Analytical Group, LLC
8350 South Kyrene Road, Suite 102
Tempe, AZ 85284

has been assessed by AClass
and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the field(s) of

CALIBRATION

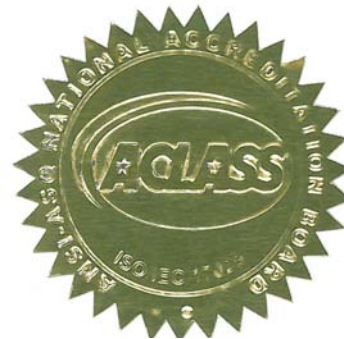
Refer to the accompanying Scope(s) of Accreditation for information regarding the types of calibrations to which this accreditation applies.

AC-1330

Certificate Number

AClass Approval

Certificate Valid 06/02/2008-06/02/2010
Version No. 001



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated January 2009).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

Evans Analytical Group, LLC

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CALIBRATION

Valid to: June 2, 2010

Certificate Number: AC-1330

I. Electromagnetic – DC / Low Frequency

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
DC Volts – Source Fixed Point	(0 to 220) mV (0.22 to 1.9) V (1.9 to 11) V (11 to 22) V (22 to 190) V (190 to 1 000) V 10 V	7.5 $\mu\text{V/V} + 0.5 \mu\text{V}$ 6.3 $\mu\text{V/V} + 1.0 \mu\text{V}$ 4.0 $\mu\text{V/V} + 3.7 \mu\text{V}$ 4.0 $\mu\text{V/V} + 6.6 \mu\text{V}$ 5.1 $\mu\text{V/V} + 0.08 \text{ mV}$ 6.7 $\mu\text{V/V} + 0.6 \text{ mV}$ 2.0 $\mu\text{V/V} + 0.11 \mu\text{V}$	Fluke 5720A Opt 03 Fluke 5725A Fluke 732A	OEM and GIDEP Sourced Calibration Procedure
DC Volts – Measure	(0 to 200) mV (0.2 to 2) V (2 to 20) V (20 to 200) V (200 to 1000) V	4.5 $\mu\text{V/V} + 0.58 \mu\text{V}$ 3.0 $\mu\text{V/V} + 0.24 \mu\text{V}$ 3.0 $\mu\text{V/V} + 0.62 \mu\text{V}$ 4.5 $\mu\text{V/V} + 0.62 \mu\text{V}$ 4.7 $\mu\text{V/V} + 5.8 \mu\text{V}$	Fluke 8508A with Fluke 5720A	OEM and GIDEP Sourced Calibration Procedure
DC Current – Measure	(0 to 200) μA (0.2 to 2) mA (2 to 20) mA (20 to 200) mA (.2 to 2) A (2 to 20) A	12 $\mu\text{A/A} + 6.1\text{nA}$ 12 $\mu\text{A/A} + 2.1 \text{ nA}$ 13 $\mu\text{A/A} + 6.2 \text{ nA}$ 36 $\mu\text{A/A} + 0.8 \mu\text{A}$ 170 $\mu\text{A/A} + 8.02 \mu\text{A}$ 380 $\mu\text{A/A} + 400 \mu\text{A}$	Fluke 8508A with Fluke 5720A	OEM and GIDEP Sourced Calibration Procedure



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)		
Resistance Measuring Equipment – Fixed Points Source	1 Ω	97.7 μΩ/Ω + 0.01 μΩ	Fluke 5720A with Fluke 8508A	OEM and GIDEP Sourced Calibration Procedure		
	1.9 Ω	97.0 μΩ/Ω + 0.01 μΩ				
	10 Ω	24.8 μΩ/Ω + 0.06 μΩ				
	19 Ω	26.2 μΩ/Ω + 0.06 μΩ				
	100 Ω	17.9 μΩ/Ω + 0.58 μΩ				
	190 Ω	17.3 μΩ/Ω + 0.58 μΩ				
	1 kΩ	9.4 μΩ/Ω + 0.58 μΩ				
	1.9 kΩ	9.5 μΩ/Ω + 0.58 μΩ				
	10 kΩ	9.5 μΩ/Ω + 5.8 μΩ				
	19 kΩ	9.5 μΩ/Ω + 5.8 μΩ				
	100 kΩ	16.1 μΩ/Ω + 0.58 mΩ	Fluke 742-1 Fluke 742-10k	OEM and GIDEP Sourced Calibration Procedure		
	190 kΩ	23.2 μΩ/Ω + 0.58 mΩ				
	1 MΩ	20.9 μΩ/Ω + 5.8 mΩ				
	1.9 MΩ	22.1 μΩ/Ω + 5.8 mΩ				
	10 MΩ	47.9 μΩ/Ω + 0.06 Ω				
	19 MΩ	65.4 μΩ/Ω + 0.06 Ω				
	100 MΩ	150.9 μΩ/Ω + 0.58 Ω				
	1 Ω	0.8 μΩ/Ω			Leeds & Northrup 4223B	OEM and GIDEP Sourced Calibration Procedure
	10 kΩ	8 μΩ/Ω				
	1 mΩ	+2.18 μΩ/Ω +100 pΩ				
10 mΩ	+2.19 μΩ/Ω +100 pΩ	Leeds & Northrup 4222B	OEM and GIDEP Sourced Calibration Procedure			
100 mΩ	+2.18 μΩ/Ω +100 pΩ	Leeds & Northrup 4221B				
100 MΩ	70 μΩ/Ω	Guildline 65206/100M Guildline 65206/1G Guildline 65206/10G	OEM and GIDEP Sourced Calibration Procedure			
1 GΩ	400 μΩ/Ω					
10 GΩ	3600 μΩ/Ω					
Resistance Measuring Equipment – Measure	1 Ω	15.1 μΩ/Ω + 2.4 μΩ	Fluke 8508A with Fluke 5720A	OEM and GIDEP Sourced Calibration Procedure		
	1.9 Ω	15.1 μΩ/Ω + 2.4 μΩ				
	10 Ω	9.3 μΩ/Ω + 8.1 μΩ				
	19 Ω	10.6 μΩ/Ω + 8.1 μΩ				
	100 Ω	15.9 μΩ/Ω + 28.9 μΩ				
	190 Ω	15.3 μΩ/Ω + 28.9 μΩ				
	1 kΩ	7.5 μΩ/Ω + 29.5 μΩ				
	1.9 kΩ	7.5 μΩ/Ω + 29.5 μΩ				
	10 kΩ	7.5 μΩ/Ω + 58.1 μΩ				
	19 kΩ	7.6 μΩ/Ω + 58.1 μΩ				
	100 kΩ	13.3 μΩ/Ω + 57.8 mΩ				
	190 kΩ	21.3 μΩ/Ω + 57.8 mΩ				
	1 MΩ	8.6 μΩ/Ω + 58.1 mΩ				
	1.9 MΩ	8.6 μΩ/Ω + 58.1 mΩ				
	10 MΩ	28.1 μΩ/Ω + 58.1 mΩ				
19 MΩ	44.9 μΩ/Ω + 57.8 Ω					



	100 MΩ	116.9 μΩ/Ω + 5.8 kΩ		
PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Resistance Measuring Equipment – Measure	100 MΩ 1 GΩ 10 GΩ 100 GΩ	505 μΩ/Ω 703 μΩ/Ω 1 002 μΩ/Ω 2 001 μΩ/Ω	Guilcline 6520	OEM and GIDEP Sourced Calibration Procedure
AC Current – Measure	(0 to 200) μA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz 200 μA to 2 mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz (2 to 20) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz (20 to 200) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz 200 mA to 2 A 10 Hz to 2 kHz (2 to 10) kHz (10 to 30) kHz (2 to 20) A 10 Hz to 2 kHz (2 to 10) kHz	310 μA/A + 20 nA 300 μA/A + 20 nA 710 μA/A + 20 nA 40 mA/A + 20 nA 310 μA/A + 200 nA 300 μA/A + 200 nA 710 μA/A + 200 nA 4.0 mA/A + 200 nA 310 μA/A + 2 μA 300 μA/A + 2 μA 710 μA/A + 2 μA 4.0 mA/A + 2 μA 310 μA/A + 20 μA 290 μA/A + 20 μA 625 μA/A + 20 μA 620 μA/A + 200 μA 725 μA/A + 200 μA 3 mA/A + 200 μA 820 μA/A + 2 mA 2.5 mA/A + 2 mA	Fluke 8508A Opt 001	OEM and GIDEP Sourced Procedures



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current – Source	<p>(2.2 to 22) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz</p> <p>(22 to 220) mA 10 to 20 Hz 20 to 40 Hz 0.04 to 1 kHz 1 to 5 kHz 5 to 10 kHz</p> <p>220 mA to 2 A 0 to 1000 Hz 1 to 5 kHz 5 to 10 kHz</p> <p>(2 to 3) A 10 to 45 Hz 0.045 to 1 kHz 1 to 5 kHz 5 to 10 kHz</p>	<p>313 $\mu\text{A/A}$ + 400 nA 220 $\mu\text{A/A}$ + 350 nA 153 $\mu\text{A/A}$ = 350 nA 240 $\mu\text{A/A}$ + 550 nA 1.27 $\mu\text{A/A}$ + 5 μA</p> <p>299 $\mu\text{A/A}$ + 4.0 μA 200 $\mu\text{A/A}$ + 3.5 μA 153 $\mu\text{A/A}$ + 2.5 μA 240 $\mu\text{A/A}$ + 3.5 μA 1.27 mA/A + 10 μA</p> <p>309 $\mu\text{A/A}$ + 35 μA 525 $\mu\text{A/A}$ + 80 μA 8.09 mA/A + 160 μA</p> <p>2.10 $\mu\text{A/A}$ + 100 μA 746 $\mu\text{A/A}$ + 100 μA 6.9 mA/A + 1 mA 28.9 mA/A + 5 mA</p>	Fluke 5720A	OEM and GIDEP Sourced Procedures



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage – Measure	<p>2.2 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>7 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>22 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>70 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>220 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p>	<p>2.7 mV/V + 1.3 μV 1.4 mV/V + 1.3 μV 0.86 mV/V + 1.3 μV 1.6 mV/V + 2 μV 2.3 mV/V + 2.5 μV 4.1 mV/V + 4 μV 5.1 mV/V + 8 μV 6.7 mV/V + 8 μV</p> <p>1.3 mV/V + 1.3 μV 0.6 mV/V + 1.3 μV 0.37 mV/V + 1.3 μV 0.68 mV/V + 2 μV 1 mV/V + 2.5 μV 2 mV/V + 4 μV 2.2 mV/V + 8 μV 3.3 mV/V + 8 μV</p> <p>0.44 mV/V + 1.3 μV 0.3 mV/V + 1.3 μV 0.18 mV/V + 1.3 μV 0.34 mV/V + 2 μV 0.49 mV/V + 2.5 μV 1.3 mV/V + 4 μV 1.5 mV/V + 8 μV 2.6 mV/V + 8 μV</p> <p>0.35 mV/V + 1.5 μV 0.18 mV/V + 1.5 μV 0.1 mV/V + 1.5 μV 0.2 mV/V + 2 μV 0.38 mV/V + 2.5 μV 0.74 mV/V + 4 μV 0.99 mV/V + 8 μV 1.6 mV/V + 8 μV</p> <p>0.3 mV/V + 1.5 μV 0.12 mV/V + 1.5 μV 0.06 mV/V + 1.5 μV 0.1 mV/V + 2 μV 0.23 mV/V + 2.5 μV 0.36 mV/V + 4 μV 0.55 mV/V + 8 μV 0.85 mV/V</p>	Fluke 5790A/03	OEM and GIDEP Sourced Procedures



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage – Measure (cont.)	700 mV		Fluke 5790A/03	OEM and GIDEP Sourced Procedures
	(10 to 20) Hz	0.3 mV/V+ 1.5 μV		
	(20 to 40) Hz	0.11 mV/V + 1.5 μV		
	40 Hz to 20 kHz	0.05 mV/V + 1.5 μV		
	(20 to 50) kHz	0.07 mV/V + 2 μV		
	(50 to 100) kHz	0.11 mV/V + 2.5 μV		
	(100 to 300) kHz	0.26 mV/V + 4 μV		
	(300 to 500) kHz	0.43 mV/V + 8 μV		
	500 kHz to 1 MHz	0.85 mV/V		
	2.2 V			
	(10 to 20) Hz	0.28 mV/V		
	(20 to 40) Hz	0.09 mV/V		
	40 Hz to 20 kHz	0.03 mV/V		
	(20 to 50) kHz	0.07 mV/V		
	(50 to 100) kHz	0.1 mV/V		
	(100 to 300) kHz	0.23 mV/V		
(300 to 500) kHz	0.37 mV/V			
500 kHz to 1 MHz	0.85 mV/V			
7 V				
(10 to 20) Hz	0.28 mV/V			
(20 to 40) Hz	0.09 mV/V			
40 Hz to 20 kHz	0.03 mV/V			
(20 to 50) kHz	0.07 mV/V			
(50 to 100) kHz	0.11 mV/V			
(100 to 300) kHz	0.27 mV/V			
(300 to 500) kHz	0.57 mV/V			
500 kHz to 1 MHz	0.85 mV/V			
22 V				
(10 to 20) Hz	0.28 mV/V			
(20 to 40) Hz	0.09 mV/V			
40 Hz to 20 kHz	0.04 mV/V			
(20 to 50) kHz	0.07 mV/V			
(50 to 100) kHz	0.11 mV/V			
(100 to 300) kHz	0.27 mV/V			
(300 to 500) kHz	0.57 mV/V			
500 kHz to 1 MHz	0.85 mV/V			
70 V				
(10 to 20) Hz	0.28 mV/V			
(20 to 40) Hz	0.1 mV/V			
40 Hz to 20 kHz	0.05 mV/V			
(20 to 50) kHz	0.08 mV/V			
(50 to 100) kHz	0.13 mV/V			
(100 to 300) kHz	0.28 mV/V			



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage – Measure (cont.)	220 V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz 700 V (20 to 50) kHz (50 to 100) kHz	0.28 mV/V 0.1 mV/V 0.04 mV/V 0.27 mV/V 0.71 mV/V	Fluke 5790A/03	OEM and GIDEP Sourced Procedures
AC Voltage Wideband -- Measure	2.2 mV (0.5 to 1.2) MHz (1 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 7 mV (0.5 to 1.2) MHz (1 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 22 mV (0.5 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 70 mV (0.5 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 220 mV (0.5 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 700 mV (1 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 2.2 V (0.5 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz 7 V (0.5 to 2) MHz (2 to 10) MHz	11 mV/V + 2.5 μV 11 mV/V + 2.5 μV 12 mV/V + 2.5 μV 14 mV/V + 2.5 μV 20 mV/V + 3.5 μV 9.2 mV/V + 8 μV 9.2 mV/V + 8 μV 9.6 mV/V + 8 μV 11 mV/V + 8 μV 14 mV/V + 8 μV 8.6 mV/V 9 mV/V 10 mV/V 13 mV/V 8.2 mV/V 9.6 mV/V 9.6 mV/V 13 mV/V 6.7 mV/V 7.4 mV/V 8.1 mV/V 11 mV/V 6.8 mV/V 7.5 mV/V 8.2 mV/V 11 mV/V 5.8 mV/V 6.5 mV/V 7.2 mV/V 11 mV/V 5.8 mV/V 6.5 mV/V	Fluke 5790A/03	OEM and GIDEP Sourced Procedures



	(10 to 20) MHz (20 to 30) MHz	7.2 mV/V 10 mV/V		
PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Electrical Simulation of Thermocouple Indicators				
Type B	(400 to 425) °C (500 to 799) °C (800 to 1 200) °C (1 300 to 1 749) °C (1 750 to 1 809) °C 1 810 °C	0.13 °C 0.15 °C 0.14 °C 0.13 °C 0.17 °C 0.18 °C	Reference Junction, Hart 9101, DC Voltage Standard (Fluke 5700A) and Agilent 34420A	OEM and GIDEP Sourced Procedures
Type J	(-190 to 232) °C (233 to 1 010) °C	0.12 °C 0.15 °C		
Type K	(-185 to 400) °C (500 to 750) °C (1 300 to 1 370) °C	0.13 °C 0.13 °C 0.18 °C		
Type R	(250 to 1 000) °C (1 200 to 1 400) °C 1 600 °C 1 750 °C	0.18 °C 0.19 °C 0.18 °C 0.20 °C		
Type T	(-210 to 400) °C (400 to 1 750) °C	0.14 °C 0.20 °C		
Inductance - Source	100 μH 1 kHz 10 kHz 1 mH 100 Hz 1 kHz 10 mH 100 Hz 1 kHz 100 mH 100 Hz 1 kHz 1 H 100 Hz 1 kHz 10 H 100 Hz 1 kHz	2.5 mH/H 2.5 mH/H 1 mH/H 1 mH/H 1.01 mH/H 1.01 mH/H 1 mH/H 1 mH/H 1.01 mH/H 1.01 mH/H 1.01 mH/H 1.01 mH/H	General Radio 1482 Series	OEM and GIDEP Sourced Procedures



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Inductance – Measure	100 μH		Agilent 4284A General Radio 1482 Series	OEM and GIDEP Sourced Procedures
	1 kHz	2.74 mH/H		
	10 kHz	1.19 mH/H		
	1 mH			
	100 Hz	5.31 mH/H		
	1 kHz	1.51 mH/H		
	10 mH			
	100 Hz	2.29 mH/H		
	1 kHz	0.83 mH/H		
	100 mH			
	100 Hz	2.02 mH/H		
	1 kHz	0.81 mH/H		
	1 H			
	100 Hz	1.01 mH/H		
1 kHz	0.81 mH/H			
10 H				
100 Hz	1.04 mH/H			
1 kHz	0.88 mH/H			

II. Thermodynamic

PARAMETER/ EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Temperature ³ – Fixed Point Calibrations:			Freezing Point Device Hart 5901CG Freeze Point of Sn Freeze Point of Zn Freeze Point of Al Freeze Point of Cu Agilent 34420A / Rosemount 162 CE	Comparison to PTB
Triple Point of Water	0.010 °C	0.0103 °C		
Freeze Point Sn	231.928 °C	0.032 °C		
Freeze Point Zn	419.527 °C	0.046 °C		
Freeze Point Al	660.323 °C	0.094 °C		
Freeze Point Cu	1084.62 °C	0.51 °C		

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Thermocouples ³ – Measure			Doric 245, freeze points, Guildline 9540, Hart 9107, NIST monograph 175 equation	OEM and GIDEP Sourced Procedures
Type R	(400 to 1 300) °C	1.1 °C	Freeze point Sn, Zn, Al, Cu	
Type B	(400 to 1 300) °C	1.4 °C		
Type J	(-40 to 750) °C	0.46 °C	Freeze point Sn, Zn, Al	
Type J	(0 to 750) °C	0.42 °C		
Type K	(-40 to 600) °C	0.49 °C	Freeze point Sn	
Type T	(-40 to 250) °C	0.28 °C		
Temperature ³ – Source Ice Point Reference	0.00 °C	0.052 °C	Hart 9101	OEM
Humidity – Source	(10 to 90) %	0.53 %	Thunder 2500	OEM

III. Mechanical

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Mass – Source	1 mg	5.8 mg/g	Mettler AT20 Mettler AT201 Mettler PR503 Mettler PR10003 Mettler KA50-5	12MSA65967B Mass Standards “Weights” 1 Year Verification Procedure
	2 mg	2.9 mg/g		
	2*mg	2.9 mg/g		
	5 mg	1.16 mg/g		
	10 mg	0.58 mg/g		
	20 mg	0.29 mg/g		
	20 *mg	0.29 mg/g		
	50 mg	0.116 mg/g		
	100 mg	58 µg/g		
	200 mg	29 µg/g		
	200 *mg	29 µg/g		
	500 mg	12 µg/g		
	1 g	12 µg/g		
	2 g	7 µg/g		
	2 *g	6 µg/g		
	5 g	4 µg/g		
	10 g	3 µg/g		
	20 g	3 µg/g		
20 *g	3 µg/g			
50 g	3 µg/g			


	100 g 200 g 200 *g 500 g 1 kg 2 kg 2 *kg 5 kg 10 kg 20 kg	3 µg/g 3 µg/g 3 µg/g 6 µg/g 0.748 mg/g 1.27 mg/g 1.27 mg/g 0.76 mg/g 66.1 µg/g 273 µg/g		
Pressure Gauges and Calibrators	(2 to 30) psig	0.00157 % of reading	Ruska 2465 with 2460-757 or 2460-706	OEM and GIDEP Sourced Calibration Procedures

IV. Dimensional

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Micrometers	(0 to 4) in	73 µin	Grade 1 Gage Blocks	OEM and GIDEP Sourced Calibration Procedures
Calipers	(0 to 6) in	(1009 + 3.5 L) µin	Grade 1 Gage Blocks	OEM and GIDEP Sourced Calibration Procedures

Notes:

1. *Best Measurement Uncertainties (Expanded Uncertainty) are based on approximately a 95% confidence interval, using a coverage of $k=2$*
2. *This laboratory's capabilities include commercial and on-site calibration services*
3. *This scope is part of and must be included with the Certificate of Accreditation No. AC-1330*



Vice President

